

ARC-635M

Environment Test Report

Report NO: 04I020008

Issued by: Rex-Chang / 10/18/2004
Test Engineer Date

Reviewed by: Wenyuan Yang / 10/18/2004
Manager Date

ARC-635M (EPOX IP-4GVI63 1.0) / 3U Rack Mounting Chassis

1. <i>Test item list</i> -----	2
2. <i>Temperature cycle operation test</i> -----	3
3. <i>Cold start test</i> -----	6
4. <i>High temperature storage test</i> -----	8
5. <i>Low temperature storage test</i> -----	10
6. <i>Humidity test</i> -----	11

Num	Item	Spec
1.	Control Box:	ARC- 635M / 3U Rack Mounting Chassis
	1. Main Board	EPOX IP-4GVI63 1.0 (BIOS ver: 09/23/2003 For Intel 845GV Chipset)
	2. CPU	Intel Pentium III / 1.0 GHz
	3. Memory	512MB Mosel V58C2256804SAT5B (DDR 333)
	4. Power Supply	Seventeam ST-300BLP 300W (ATX)
	5. HDD	Seagate ST33221A 3.2GB
	6. CD-ROM	LITE-ON LTN-526S 52X
	7. FDD	TEAC FD-235HF

CPU Cooler



ARC-635M (EPOX IP-4GVI63 1.0) / 3U Rack Mounting Chassis

Test Date: 10-14~16-2004

Test Product: ARC-635M / 3U Rack Mounting Chassis (EPOX IP-4GVI63 1.0).

Test Site: AAEON QA Internal Lab.

Performed By: Rex Chang

Test Standard:

Reference IEC 68-2-61 Testing procedures
Test Z/ABD: Climatic Sequence Test

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 05/24/04
Serial Number: 1241

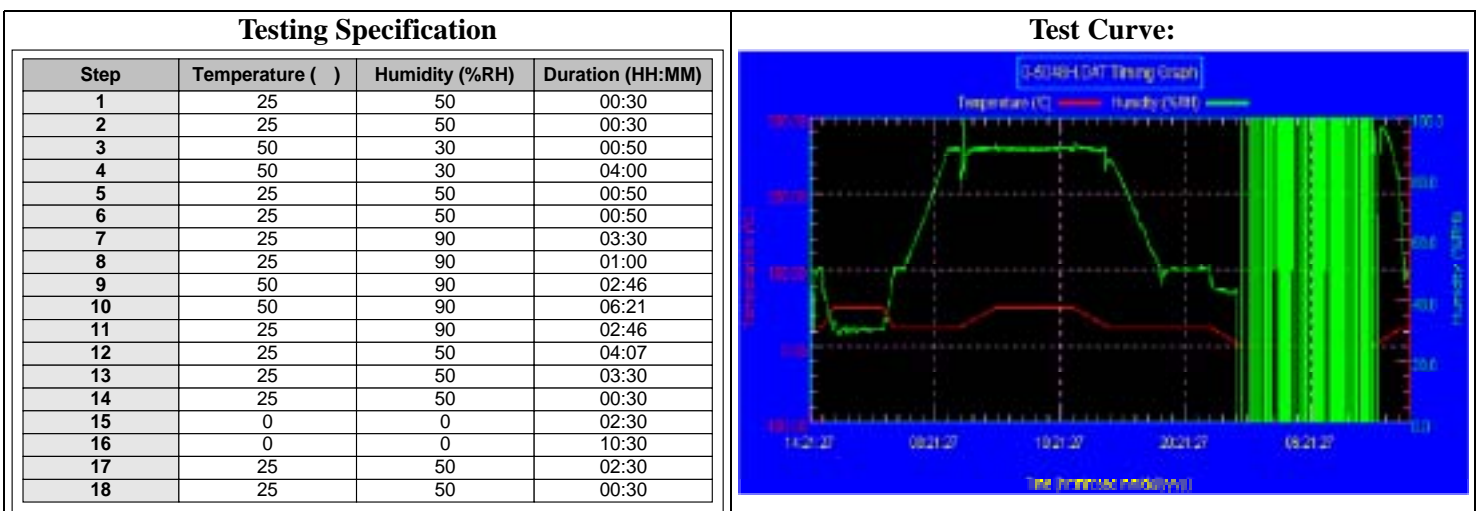
Temperature Measurement:

20 Channel Thermal Recorder:
YOKOGAWA Inc,
Model: DA100-13-1D
Date of Calibration: 12/25/03
Serial Number: 12A323190

Test O.S. / Software:

Windows 2000 / Run six Microsoft media player simultaneously.

Temperature & Humidity Cycle Test:



Sample Configuration & Quantity Under Test:

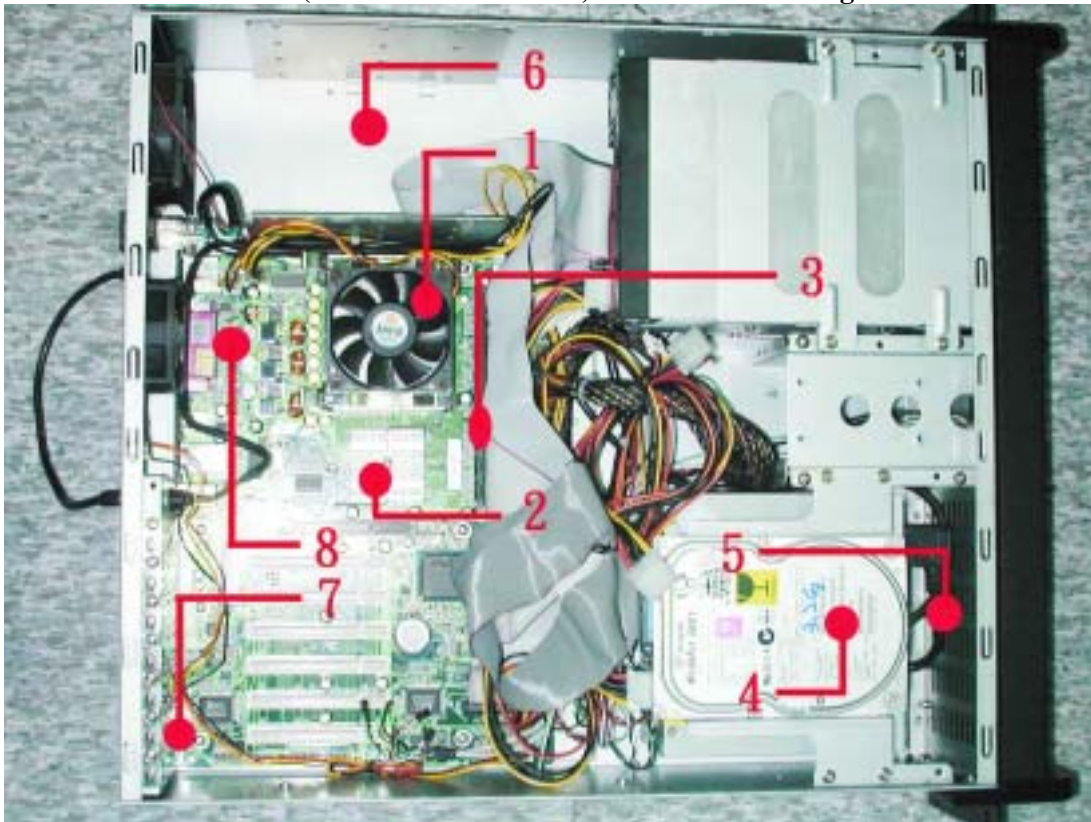
Using one ARC-635M (EPOX IP-4GVI63 1.0) / 3U Rack Mounting Chassis

ARC-635M (EPOX IP-4GVI63 1.0) / 3U Rack Mounting Chassis

Temperature Recorder:

Measuring Accelerometer Position:

ARC-635M (EPOX IP-4GVI63 1.0) / 3U Rack Mounting Chassis



ARC-635M (EPOX IP-4GVI63 1.0) / 3U Rack Mounting Chassis

Thermal profile data:

ARC-635M (EPOX IP-4GVI63 1.0) / 3U Rack Mounting Chassis

Point	Temp. Stage		
	50	25	0
1. CPU	75.8	50.9	24.5
2. Intel 82845GV Chipset	72.0	46.6	20.4
3. Memory	72.5	46.4	20.9
4. HDD Surface	62.1	38.2	13.0
5. Control Box Inside Air Temperature - 1	60.9	35.2	9.5
6. Control Box Inside Air Temperature - 2	57.9	32.7	8.0
7. Control Box Inside Air Temperature - 3	59.4	35.4	9.9
8. Control Box Inside Air Temperature - 4	62.4	37.5	12.1
9. Control Box. External Surface	55.2	31.8	8.1
10. Chamber Air Temperature	51.5	27.1	2.3

Sample Configuration & Quantity Under Test:

Quantity: 1 (ARC-635M / 3U Rack Mounting Chassis)

Test Result:

The system structure doesn't deformation; Function is OK during system test.

ARC-635M (EPOX IP-4GVI63 1.0) / 3U Rack Mounting Chassis

Test Date: 09-29~30-2004

Test Product: ARC-635M (EPOX IP-4GVI63 1.0) / 3U Rack Mounting Chassis

Test Site: AAEON QA Internal Lab.

Performed By: Rex Chang

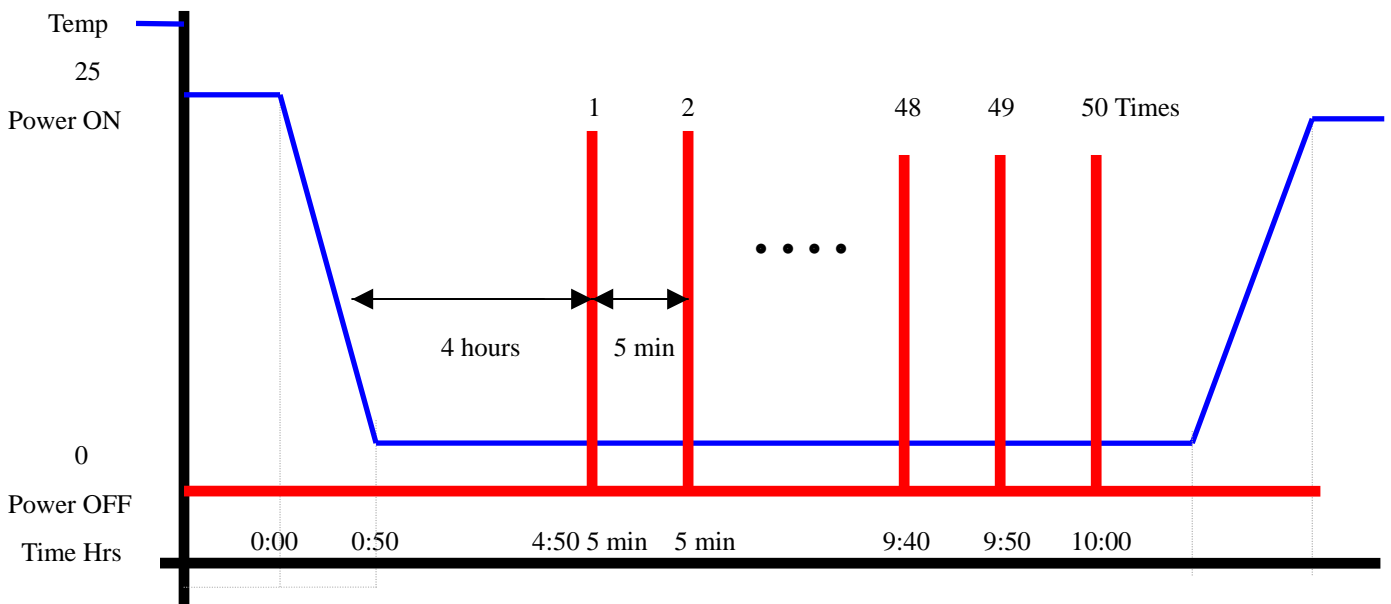
Test Standard: Reference IEC 68-2-1 Testing procedures
Test Ab: Cold Test

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 10/17/03
Serial Number: 2582

Test Condition:

1. Test Temperature: 0
2. Test Times: 5 Hours or 50 times of ON/OFF
 - (1) Power off for 4 hours before 1'st power on. Then once complete boot, power off immediately.
 - (2) After 5 min later power on again and wait until booting is completed.
 - (3) Repeat (2) for around 4:50
 - (4) Power off then wait for 5 min before final power on operation.
3. Number of test: 50 times
4. Test Software: Windows 2000
5. Test Environment Curve:



ARC-635M (EPOX IP-4GVI63 1.0) / 3U Rack Mounting Chassis

Sample Configuration & Quantity Under Test:

Quantity: 1 (ARC-635M / 3U Rack Mounting Chassis)

Test Result:

Passed.

ARC-635M (EPOX IP-4GVI63 1.0) / 3U Rack Mounting Chassis

Test Date: 09-27~29-2004

Test Product: ARC-635M (EPOX IP-4GVI63 1.0) / 3U Rack Mounting Chassis

Test Site: AAEON QA Internal Lab.

Performed By: Rex Chang

Test Standard: Reference IEC 68-2-2 Testing procedures
Test Bb: Dry Heat Test (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4L+-100
Date of Calibration: 10/17/03
Serial Number: 2582

Testing Item:

1. Test Temperature: 60
2. Test Times: 48Hrs
3. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (ARC-635M / 3U Rack Mounting Chassis)

Test Result:

1. After high temperature storage test, the structure of chassis never change shape and surface paint doesn't flake off.
2. The system all functions are OK after high temperature storage test.

ARC-635M / 3U Rack Mounting Chassis

Test Date: 10-09~11-2004

Test Product: ARC-635M / 3U Rack Mounting Chassis

Test Site: AAEON QA Internal Lab.

Performed By: Rex Chang

Test Standard: Reference IEC 68-2-2 Testing procedures
Test Bb: Dry Heat Test (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4L+-100
Date of Calibration: 10/17/03
Serial Number: 2582

Testing Item:

- 4. Test Temperature: 80
- 5. Test Times: 48Hrs
- 6. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (ARC-635M / 3U Rack Mounting Chassis)

Test Result:

After high temperature storage test, the structure of chassis never change shape and surface paint doesn't flake off.

ARC-635M (EPOX IP-4GVI63 1.0) / 3U Rack Mounting Chassis

Test Date: 09-24~27-2004

Test Product: ARC-635M (EPOX IP-4GVI63 1.0) / 3U Rack Mounting Chassis

Test Site: AAEON QA Internal Lab.

Performed By: Rex Chang

Test Standard: Reference IEC 68-2-1
Testing procedures Test Ab: Cold Test (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 10/17/03
Serial Number: 2582

Testing Item:

1. Test Temperature: -20
2. Test Times: 48Hrs
3. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (ARC-635M / 3U Rack Mounting Chassis)

Test Result:

1. After high temperature storage test, the structure of chassis never change shape and surface paint doesn't flake off.
2. The system all functions are OK after high temperature storage test.

ARC-635M (EPOX IP-4GVI63 1.0) / 3U Rack Mounting Chassis

Test Date: 09-07~09-2004

Test Product: ARC-635M (EPOX IP-4GVI63 1.0) / 3U Rack Mounting Chassis

Test Site: AAEON QA Internal Lab.

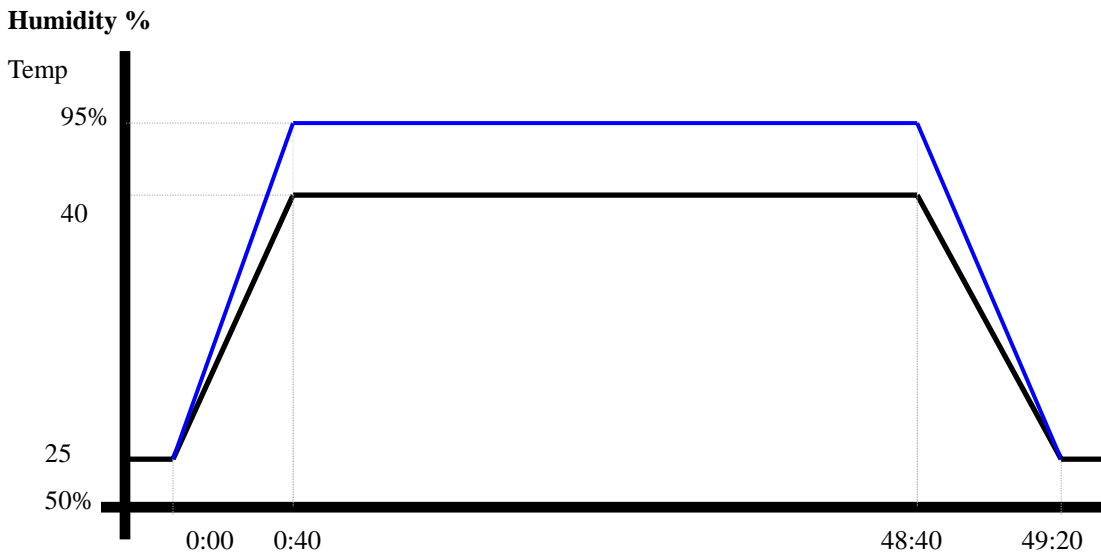
Performed By: Rex Chang

Test Standard: Reference IEC 68-2-3 Testing procedures
Test Ca: Damp heat, steady state (Non-operation)

Test Equipment:
Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 10/17/03
Serial Number: 2582

Testing Item:

1. Test Temperature: 40
2. Test Humidity: 95%RH
3. Test Times: 48Hrs
4. Test Environment Curve:



Sample Configuration & Quantity Under Test:
Quantity: 1 (ARC-635M / 3U Rack Mounting Chassis)

Test Result:

1. After high temperature storage test, the structure of chassis never change shape and surface paint doesn't flake off.
2. The system all functions are OK after high temperature storage test.